

## Notice of References Cited

<b>*</b>		
Application/Control No.	Applicant(s)/Pate	nt Under
09/994,189	Reexamination LINDNER ET AL.	
Examiner	Art Unit	
Huy Q Phan	2685	Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-2002/0160812 A1	10-2002	Moshiri-Tafreshi et al.	455/561
	В	US-2002/0082032 A1	06-2002	Hunzinger, Jason F.	455/510
	С	US-6,658,249 B1	12-2003	Hietalahti et al.	455/422.1
	D	US-6,519,233 B1	02-2003	Gutierrez, Alberto	370/320
, i	Е	US-6,594,241 B1	07-2003	Malmlof, Jim	370/329
	F	US-6,665,307 B1	12-2003	Rydnell et al.	370/437
	G	US-			
	Н	US-			
	ı	US-			
	J	US-			
	К	US-			
	L	US-			
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Q					
	R					
	s					
	Т					

## **NON-PATENT DOCUMENTS**

*	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)				
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V					
W					
×	,				

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